

第60回 GMSI公開セミナー

Meeting great men
Cambridge, 1955-1965Professor **David Brandon**Faculty of Materials Engineering, Technion,
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Haifa 32000, Israel日時: 2010年 7月7日(水) 13:30-15:00
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要旨

For this young metallurgist, the decade 1955-1965 was life-changing. The decade began with the development of thin-film electron microscopy and the quantitative analysis of diffraction contrast from crystal lattice defects. The pioneers were **Peter Hirsch** and his research group in the Cavendish Laboratory, but the Metallurgy Department had developed replicas for the electron microscopy of ferrous and non-ferrous alloys and I was one of their research students. **Gareth Thomas** held a post-doctoral appointment and the group, led by **Jack Nutting**, included **Robin Nicholson**, **Pat Kelly** and **Peter Swann**. We adapted the electro-polishing method to prepare thin-film samples from a wide range of aluminum alloys, steels and copper alloys.

By mid-decade, **Mike Ashby** and I had been awarded British Council Scholarships to visit Germany, where we met with **Alfred Seeger**, **Peter Haasen** and others. A continuous stream of distinguished visitors came to Cambridge: **John Cahn**, **Jock Eshelby**, **Jacques Friedel** and **Charles Frank**, all gave lectures and spent hours talking to research students, showing endless patience for our many scientific misconceptions. In addition, **Erwin Müller**, **Alan Cottrell**, **Piers Bowden**, **Mike Southon**, **Srinivasa Ranganathan**, **Mike Wald**, **Brian Ralph**, **Walter Bollmann**, **Mike Southon**, **Cyril Stanley Smith**, **H. Hashimoto**, **John Hilliard**, **Yoichi Ishida**, **Robert Gomer** and many others will be introduced. Being in Cambridge at the birth of thin-film electron microscopy was a privilege, but being given the opportunity to image coincident site boundaries in the field-ion microscope was extraordinary luck. None of it could have happened without the guidance provided by a remarkable galaxy of memorable scientists.